

**RELIABILITY REPORT
FOR**

DS3070W, Rev A, RoHS

Dallas Semiconductor

**4401 South Beltwood Parkway
Dallas, TX 75244-3292**

Prepared by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Dallas Semiconductor products and processes:

DS3070W, Rev A, RoHS

In addition, Dallas Semiconductor's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.*

Module Description

A description of this Module can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.*

Reliability Derating:

A module device consists of one or more IC's in a single, upward integrated, package. This package is assembled to include batteries, crystals, and other piece parts that make up the configuration of the Module. Because of either the complexity of the package or the included piece parts, standard high temperature reliability testing is not possible. Therefore, in order to determine the reliability of module products, the reliability of each of the piece parts is individually determined, then summed to determine the reliability of the integrated module product. If there are "n" significant components in the module then:

$$Fr(\text{module}) = Fr(1) + Fr(2) + Fr(3) + \dots + Fr(n)$$

Fr (module) = Failure rate of module
 Fr(n) = Failure rate of the nth component

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$MTTF = 1/Fr$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this module/assembly is:

<u>Module Device:</u>	<u>Module Units:</u>	<u>Quantity:</u>	<u>Fails:</u>	<u>Ea:</u>	<u>Beta:</u>	<u>MTTF (Yrs):</u>	<u>FITs:</u>
16 MEG SRAM 3V	1	135	0	0.5	2.4	102505	1.1
CRYSTAL	1	100	0	0.7	0.0	12463	9.2
DS1310	1	1862	0	0.7	0.0	211624	0.5
ML2020R	1	45	0	0.7	0.0	3527	32.4
Totals:						2644	43.2

The parameters used to calculate the module failure rate are as follows

Cf: 60% Tu: 25 °C Vu: 3 Volts

The reliability data follows. At the start of this data is the module assembly information. This is a description of the module. The next section is the detailed reliability data for each stress found in the qualification / monitor. If there are additional processes or assemblies used as part of this report, a description of each will follow which includes the respective reliability data for that process/ assembly. The reliability data section includes the latest data available. Some of this data may be generic with other packages or products.

* Some proprietary products may be excepted from this requirement

Assembly Information:

Assembly Site: Dallas
 Pin Count: 256
 Package Type: Single Piece BGA Module w/Battery & Crystal (Server RoHS)
 Body Size: 27x27x7.9
 Mold Compound: NA
 Lead Frame: PCB; BT
 Lead Finish: SnPb Ball (63/37)
 Die Attach: n/a
 Bond Wire / Size: Au / 1.0 mil
 Flammability: UL 94-V0
 Moisture Sensitivity (JEDEC J-STD20A) Level 3
 Date Code Range: 0606 to 0615

PACKAGE TESTS

DESCRIPTION	DATE CD	CONDITION	READPOINT	QTY	FAILS	FA#
X-RAY	0606	MIL-STD-883-2012 : TOP & SIDE VIEW		6	0	
PHYSICAL DIMENSIONS		JESD22-B100		6	0	
MARK PERMANENCY		JESD22-B107		6	0	
BALL SHEAR		JESD22-B117		6	0	
EXTERNAL VISUAL		JESD22-B101		6	0	
Total:					0	

PRECONDITIONING LEVEL 3

DESCRIPTION	DATE CD	CONDITION	READPOINT	QTY	FAILS	FA#
STORAGE LIFE	0606	125C	48 HRS	275		
MOISTURE SOAK		30C/60% R.H.	192 HRS	275		
CONVECTION REFLOW		220C +5/-0C	2 PASS	275		
GROSS LEAK		25 C, AIR PRESSURE DECAY		275	0	
EXTERNAL VISUAL		JESD22-B101		275	0	

FOLLOWED BY: **Total: 0**

MECHANICAL LIFE

DESCRIPTION	CONDITION	READPOINT	QTY	FAILS	FA#
VIBRATION, VARIABLE FREQUENCY	10g or 0.06", 5Hz-2KHz, X Y Z axis	9 HRS	22	0	
MECHANICAL SHOCK	200G, 1/2 SINE, 6 MS	30 CYS	22	0	
Total:				0	

STORAGE LIFE

DESCRIPTION	CONDITION	READPOINT	QTY	FAILS	FA#
STORAGE LIFE	85 C	1000 HRS	77	0	
Total:				0	

TEMPERATURE CYCLE

DESCRIPTION	CONDITION	READPOINT	QTY	FAILS	FA#
TEMP CYCLE	-40 TO 85C	1000 CYS	77	0	
Total:				0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	CONDITION	READPOINT	QTY	FAILS	FA#
FLUX DIP & H2O RINSE	JESD22-A113	1 HRS	77	0	
BIASED MOISTURE (BATTERY)	60C/90% R.H., BATTERY BIAS	1000 HRS	77	0	
Total:				0	

CONSTRUCTION ANALYSIS

DESCRIPTION	DATE CD	CONDITION	READPOINT	QTY	FAILS	FA#
PACKAGE, ASSEMBLY PROCESS	0606	TO BE DONE BY F/A	2	3	0	
Total:				0		

PACKAGE TESTS

DESCRIPTION	DATE CD	CONDITION	READPOINT	QTY	FAILS	FA#
X-RAY	0615	MIL-STD-883-2012 : TOP & SIDE VIEW		6	0	
PHYSICAL DIMENSIONS		JESD22-B100		6	0	
MARK PERMANENCY		JESD22-B107		6	0	
BALL SHEAR		JESD22-B117		6	0	
EXTERNAL VISUAL		JESD22-B101		6	0	
Total:				0		

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MECHANICAL LIFE

DESCRIPTION	CONDITION	READPOINT	QTY	FAILS	FA#
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